

**Notice of References Cited**

Application/Control No.

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Applicant(s)/Patent Under  
Reexamination  
HESLINE, RAYMOND

Examiner

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Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-2003/0020989	01-2003	Liu et al.	359/161
*	C	US-2003/0147136	08-2003	Pan et al.	359/484
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**NON-PATENT DOCUMENTS**

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